

CYPRESS SEMICONDUCTOR

PRODUCT CHANGE NOTIFICATION

PCN:020027

DATE: October 25, 2002

Subject: Fab Location change for IMIZ9972/ IMIZ9973/IMIZ9974/IMIB9940/IMIZ9948 from IBM to Chartered Semiconductor

To:

Description of change:

The Fab location will be changed for devices IMIZ9972, IMIZ9973, IMIZ9974, IMIB9940, IMIZ9948 from IBM to Chartered Semiconductor Manufacturing. Refer to the table below for ordering part#

OLD PART#	NEW ORDERING PART#
IMIB9940	CY29940
IMIZ9948	CY29948
IMIZ9972	CY29972
IMIZ9973	CY29973
IMIZ9974	CY29974

Benefit of change:

Improved availability and long term support.

Qualification status:

Completed. QTP# I000002

Sample status:

Contact our sales office for samples

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Cypress part numbers affected:

IMIZ9972, IMIZ9973, IMIZ9974, IMIB9940, IMIZ9948

Customer part numbers affected:

Approximate Implementation Date:

Production release of the new product will be implemented as per your response requirements or WW 02 2003.

Response Required:

Sincerely,

Mike Burke
Director of Quality

Al Laxman
PCN Process Manager



CYPRESS

**QUALIFICATION
SUMMARY
QTP# I000002**

Cypress Semiconductor
3901 North First Street
San Jose, CA 95134
Phone: (408) 943-2600 Fax: (408) 943-2796

DIE QUALIFICATION TEST RESULTS

D35C/E35C/F35C base die platform (0.35 μ M, 3 layers metal, CMOS, CSM-Singapore)

Test	Military or Industry Standard	Conditions	Test Points	Test Results	Comments
Life Test	MIL-STD-883 Method 1005	150°C/3.3V	168 332	0/116 0/116	Lot C1061-D35C
Life Test	MIL-STD-883 Method 1005	150°C/3.3V	72 596	0/116 0/116	Lot C1024-D35C
Life Test	MIL-STD-883 Method 1005	150°C/3.3V	168	0/116	Lot C1130-D35C
ESD	MIL-STD-883 Method 3015	HBM	2000V 3000V 4000V 5000V	0/3 0/3 0/3 0/3	Lot C1214-D35C
Latch-up	JESD78		200 Ma	0/5	Lot C1214-D35C
ESD	MIL-STD-883 Method 3015	HBM	2000V 3000V 4000V	0/3 0/3 0/2	Lot C1281-E35C
Latch-up	JESD78		200 mA	0/5	Lot C1281-E35C
ESD	MIL-STD-883 Method 3015	HBM	2000V 3000V 4000V	0/3 0/3 0/2	Lot C1189-F35C
Latch-up	JESD78		200 mA	0/5	Lot C1189-F35C

PACKAGE QUALIFICATION TEST RESULTS

SOIC ,0.150 wide

Test	Military or Industry Standard	Conditions	Test Points	Test Results	Comments
Temperature Cycle	MIL-STD-883 Method 1010	500 cycles, -65/+ 150°C	500	0/76	Preconditioned Units, CWT, lot C1179
Pressure Pot	JEDEC Std. 22 Test Method 102	168 Hours, 100% RH, 121°C, 2 atm	168	0/76	Preconditioned Units, CWT, lot C1179
Temperature Cycle	MIL-STD-883 Method 1010	500 cycles, -65/+ 150°C	500	0/76	Preconditioned Units, SPEL, lot T2959
Pressure Pot	JEDEC Std. 22 Test Method 102	168 Hours, 100% RH, 121°C, 2 atm	168	0/76	Preconditioned Units, SPEL, lot T2959
Temperature Cycle	MIL-STD-883 Method 1010	500 cycles, -65/+ 150°C	500	0/76	Preconditioned Units, CWT, lot B6399
Pressure Pot	JEDEC Std. 22 Test Method 102	168 Hours, 100% RH, 121°C, 2 atm	168	0/76	Preconditioned Units, CWT, lot B6399
Temperature Cycle	MIL-STD-883 Method 1010	500 cycles, -65/+ 150°C	500	0/76	Preconditioned Units, SIG-K, lot F5216
Pressure Pot	JEDEC Std. 22 Test Method 102	168 Hours, 100% RH, 121°C, 2 atm	168	0/76	Preconditioned Units, SIG-K, lot F5216
Physical Dimension	JEDEC Spec.	Applicable drawing	N/A	0/12	Performed by CWT
Resistance to Solvent	MIL-STD-883 Method 2015		N/A	0/12	Performed by CWT
Solderability	MIL-STD-883 Method 2003	260 Deg, 5 sec 95% Min Covrg	N/A	0/5	Performed by CWT
Coplanarity	JEDEC Spec.	Max = 4 Mil	N/A	0/20	Performed by CWT
Physical Dimension	JEDEC Spec.	Applicable drawing	N/A	0/12	Performed by SPEL
Resistance to Solvent	MIL-STD-883 Method 2015		N/A	0/12	Performed by SPEL
Solderability	MIL-STD-883 Method 2003	260 Deg, 5 sec 95% Min Covrg	N/A	0/5	Performed by SPEL
Coplanarity	JEDEC Spec.	Max = 4 Mil	N/A	0/20	Performed by SPEL
Physical Dimension	JEDEC Spec.	Applicable drawing	N/A	0/12	Performed by SIG-K
Resistance to Solvent	MIL-STD-883 Method 2015		N/A	0/12	Performed by SIG-K
Solderability	MIL-STD-883 Method 2003	260 Deg, 5 sec 95% Min Covrg	N/A	0/5	Performed by SIG-K
Coplanarity	JEDEC Spec.	Max = 4 Mil	N/A	0/20	Performed by SIG-K